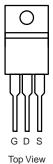


AUL2203N-VB Datasheet

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	30				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0. 0020				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0. 0028				
I _D (A)	140				
Configuration	Single				

TO-220AB

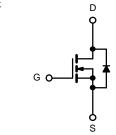


FEATURES

- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2011/65/EU

APPLICATIONS

- OR-ing
- Server ٠
- DC/DC



N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		140 ^{a, e}	_	
Continuous Droin Current $(T = 175 °C)$	T _C = 70 °C		110 ^e		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	39 ^{b, c}	A	
	T _A = 70 °C		28 ^{b, c}	A	
Pulsed Drain Current	I _{DM}	370			
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39		
Single Pulse Avalanche Energy	L = 0.1 IIIA	E _{AS}	375	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	90 ^{a, e}	٨	
Continuous Source-Drain Diode Current	T _A = 25 °C	IS	3.13 ^{b, c}	— A	
	T _C = 25 °C		250 ^a		
Maximum Power Dissipation	T _C = 70 °C	Б	175	10/	
	T _A = 25 °C	P _D	3.75 ^{b, c}		
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	0,00	

Notes: a. Based on $T_C = 25 \ ^{\circ}C$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 sec.
d. Maximum under steady state conditions is 90 °C/W.
e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Demonstration .	1	rwise noted)		The second		11	
Parameter Static	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 µA	30			V	
V _{DS} Temperature Coefficient	VDS ΔV _{DS} /T _{.1}	V _{GS} = 0 V, I _D = 230 μA	30	25		v	
	20 0	I _D = 250 μA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		4.0	- 7.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$ 1.			3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 V V_{GS} = 0 V$			1	μA	
On State Drain Current	1	$V_{DS} = 24 \text{ V } V_{GS} = 0 \text{ V}, \text{T}_{\text{J}} = 55 ^{\circ}\text{C}$ $V_{DS} \ge 5 \text{ V}, \text{V}_{GS} = 10 \text{ V}$	00		10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} = 30$ V, $V_{GS} = 10$ V V _{GS} = 10 V, I _D = 38.8 A	90	0.0000		A	
Drain-Source On-State Resistance ^a	R _{DS(on)}			0.0020		Ω	
F		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 37 \text{ A}$		0.0028			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S	
Dynamic ^b			[0.400	[1	
Input Capacitance	C _{iss}			8400		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz$		1725			
Reverse Transfer Capacitance	C _{rss}			970			
Total Gate Charge	Q_g $V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_D = 38.8 \text{ A}$		171	257	-		
Gate-Source Charge	Q _{gs}	V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 28.8 A		81.5 34	123	nC	
Gate-Drain Charge	Q _{gd}	VDS = 10 V, VGS = 4.0 V, ID = 20.0 / V		29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	0			1.4	2.1	ns	
Rise Time	t _{d(on)} t _r	V _{DD} = 15 V, R _I = 0.625 Ω		10	17		
Turn-Off Delay Time	t _{d(off)}	$V_{\text{DD}} \simeq 13$ V, $N_{\text{L}} \simeq 0.023$ M $I_{\text{D}} \simeq 24$ A, $V_{\text{GEN}} = 10$ V, $R_{\text{g}} = 1$ Ω		70	105		
Fall Time	t _f	D , GLN - , g		10	15		
Turn-On Delay Time				55	83		
Rise Time	t _{d(on)} t _r	V_{DD} = 15 V, R ₁ = 0.67 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$V_{\text{DD}} = 13 \text{ V}, \text{ KL} = 0.07 \Omega^2$ $I_{\text{D}} \cong 22.5 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		55	83		
Fall Time	t _f	.D = GEN		12	18		
Drain-Source Body Diode Characteristic				12	10		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		140		1	
Pulse Diode Forward Current ^a				370		A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		27	100	ns	
Reverse Recovery Rise Time	t _a			27			

Notes:

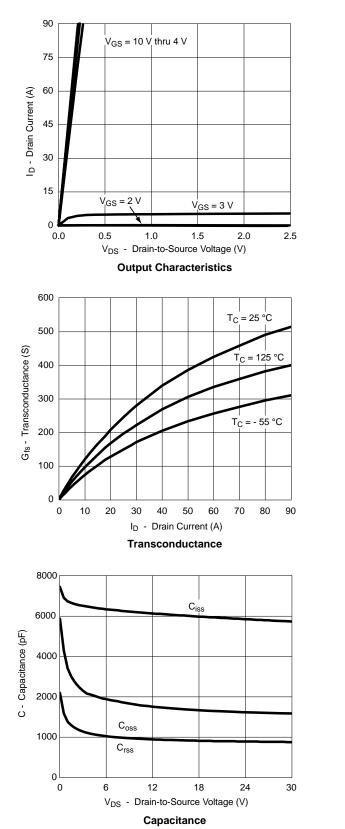
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

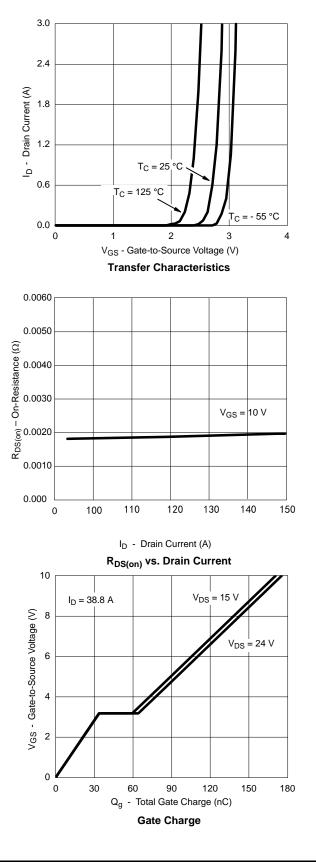
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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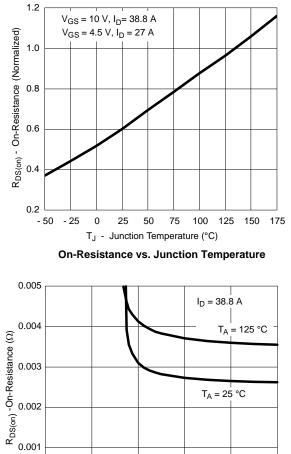


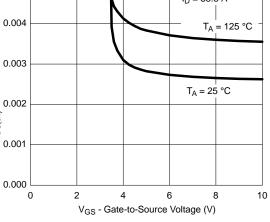
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

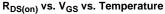


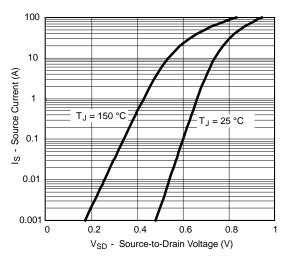


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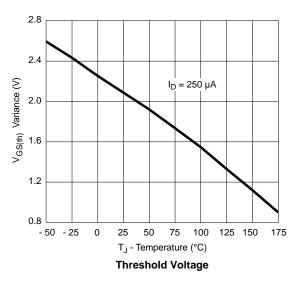


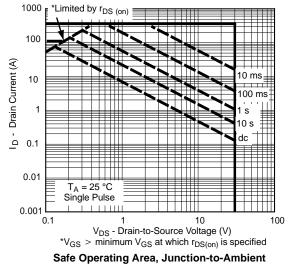




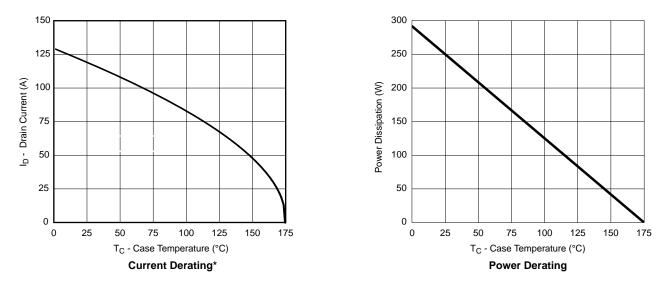






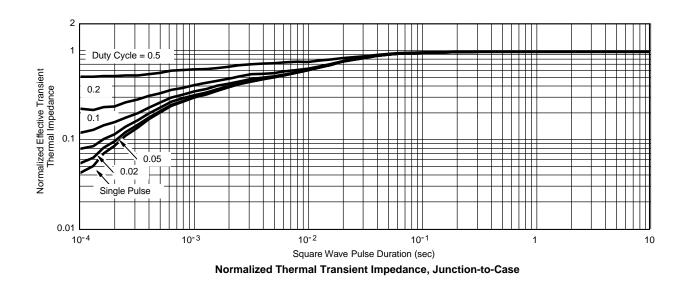






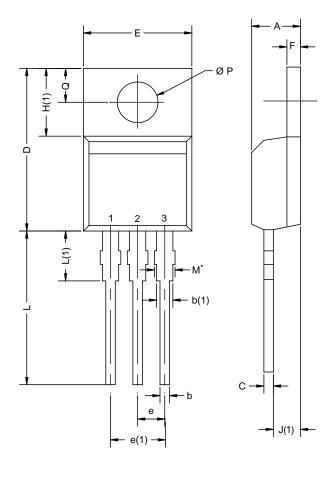
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-220AB



	MILLIN	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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